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EECS151 : Introduction to Digital Design and ICs

Lecture 11 – CMOS

Bora Nikolić



RISC-I: Reduced Instruction Set Computing

On February 12, 2015, IEEE installed a plaque at UC Berkeley to commemorate the contribution of RISC-I. The plaque reads:

UC Berkeley students designed and built the first VLSI reduced instruction-set computer in 1981. The simplified instructions of RISC-I reduced the hardware for instruction decode and control, which enabled a flat 32-bit address space, a large set of registers, and pipelined execution. A good match to C programs and the Unix operating system, RISC-I influenced instruction sets widely used today, including those for game consoles, smartphones and tablets.



<https://risc.berkeley.edu/risc-i/reunion/>

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Review

- Pipelining increases throughput
 - Structural, control and data hazards exist
- FPGAs are widely used for hardware prototyping and accelerating key applications.
- Core FPGA building blocks:
 - Configurable Logic Blocks (CLBs)
 - Slices
 - Look-Up Tables
 - Flip-Flops
 - Carry chain
 - Configurable Interconnect

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FPGA Interconnect

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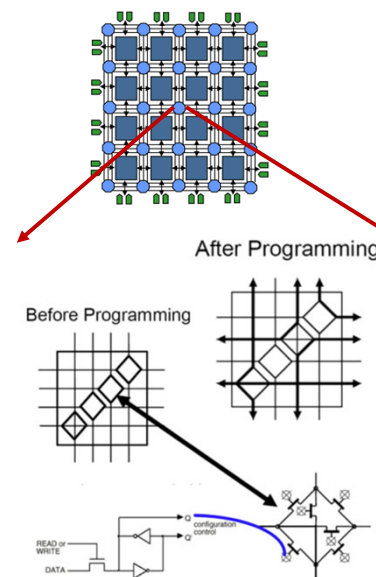
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Configurable Interconnect

- Between rows and columns of CLBs are wiring channels.
- These are programmable. Each wire can be connected in many ways.
- Switch Box:
 - Each interconnection has a transistor switch.
 - Each switch is controlled by 1-bit configuration register.



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FPGA Features: BRAMs, DSP, AI

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Diverse Resources on FPGA

Colors represent
different types of
resources:

Logic

Block RAM

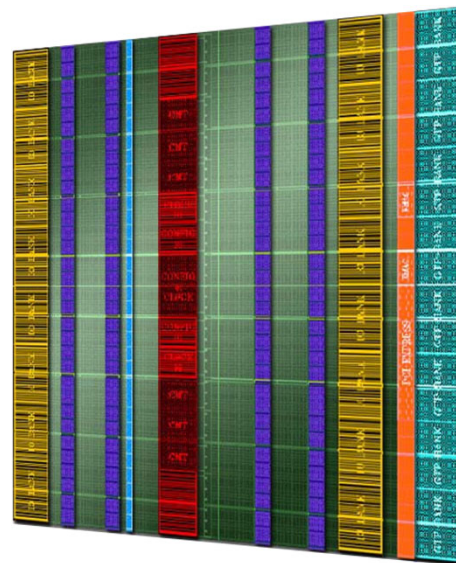
DSPs

Clocking

I/O

Serial I/O + PCI

A routing fabric runs
throughout the chip to
wire everything
together.



Virtex-5 Die Photo
[Xilinx]

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Block RAM

- Block Random Access Memory
- Used for storing large amounts of data:
 - 18Kb or 36Kb
 - Configurable bitwidth
 - 2 read and write ports
- More recently
 - UltraRAM in UltraScale+ devices

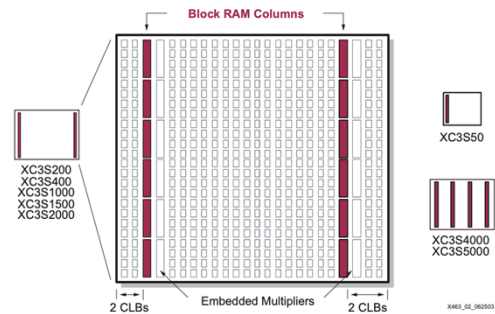
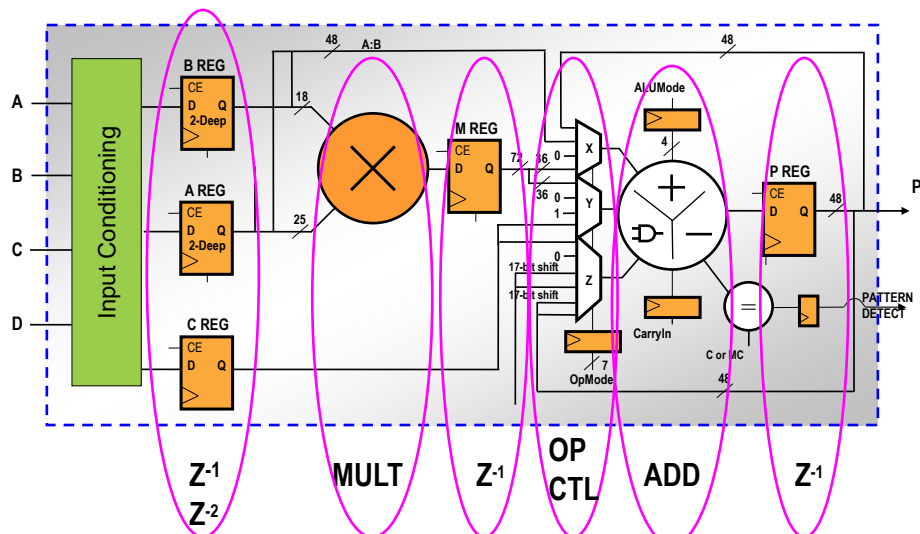


Figure 2: Block RAMs Arranged in Columns with Detailed Floorplan of XC3S200

Xilinx Datasheet

DSP Slice

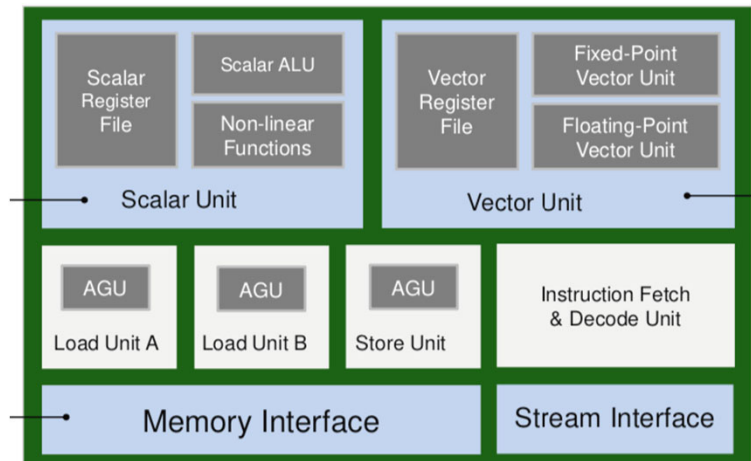


Efficient implementation of multiply, add, bit-wise logical.

Xilinx Resource

AI Engine

- Versal AI Core



Xilinx HotChips'2019

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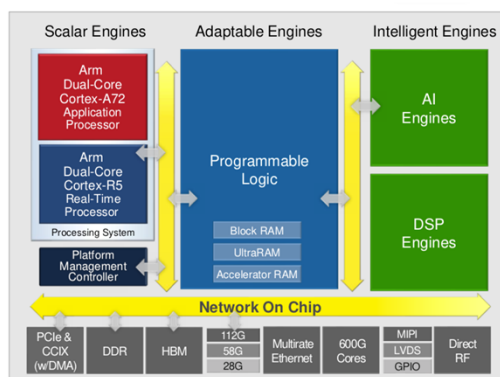
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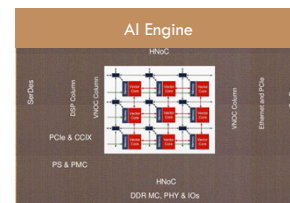
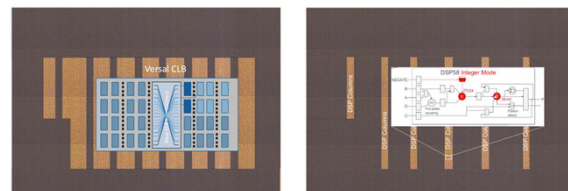
State-of-the-art Xilinx FPGA Platform

- Versal (ACAP: Adaptive Compute Acceleration Platform)



Xilinx HotChips'2019

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CMOS Process

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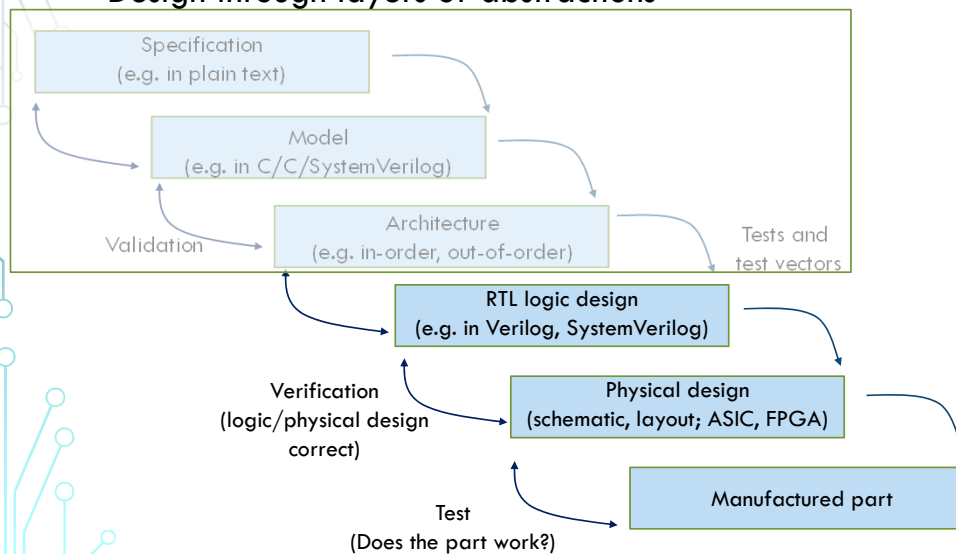
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Design Process

- Design through layers of abstractions



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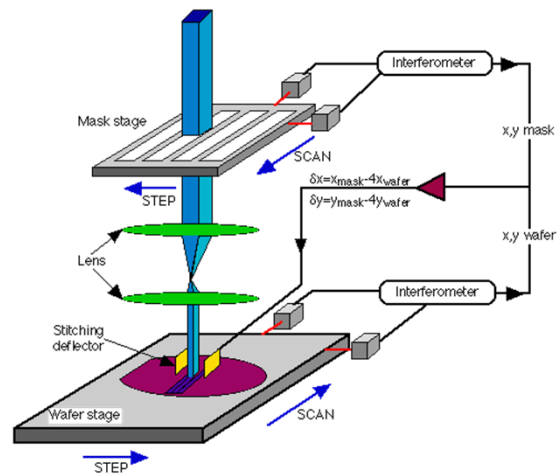
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Step-and-Scan Lithography



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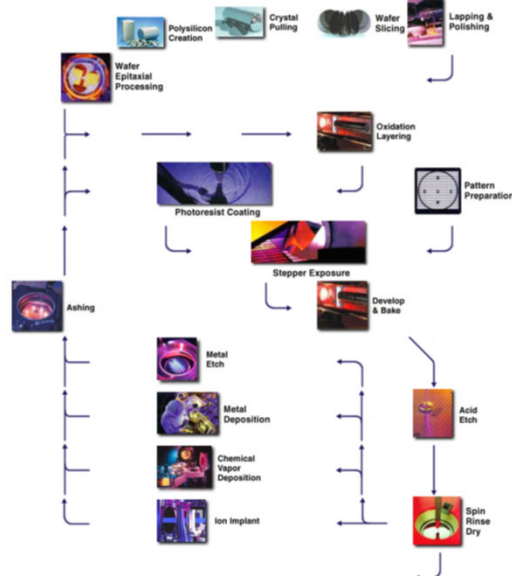
Semiconductor Manufacturing

• Repetitive steps (40-70 masks):

- Passivation
- Photoresist coating
- Patterning (stepper)
- Develop
- Etch
- Process step
 - Etching
 - Deposition
 - Implant
- Remove resist
- Repeat

• Zoom into a chip:

<https://youtu.be/Fxv3JoS1uY8>



<http://laplace.ucv.cl/Charlas/Semiconductors/Chip/semiconductors.html>

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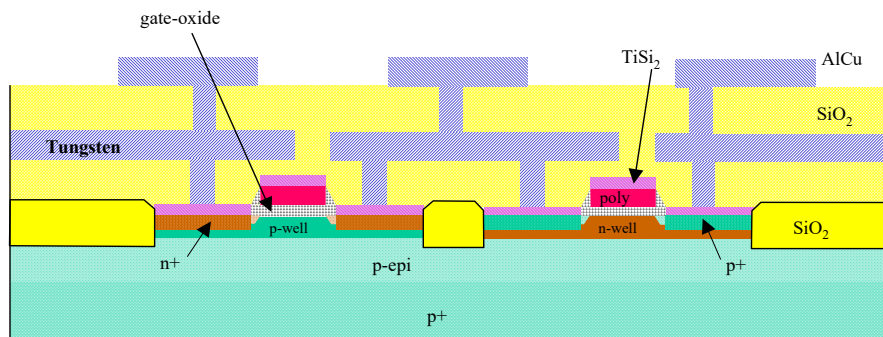
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CMOS Process

- Post $\sim 250\text{nm}$ CMOS
- Shallow-trench isolation, dual/triple-well process



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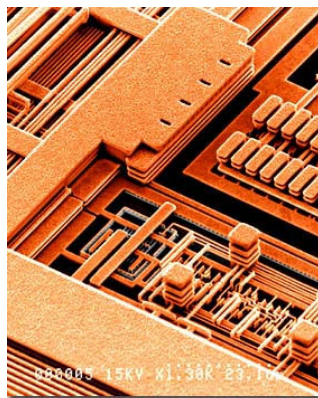
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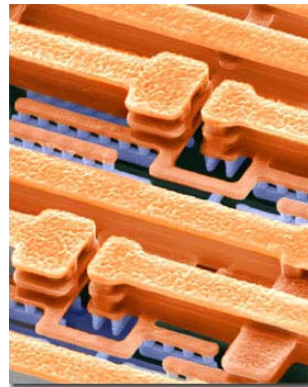
15

Metal Stack

- Interconnect is predominantly copper



SEM view of Copper Interconnect
(IBM Microelectronics)



SEM view of Copper Interconnect
(IBM Microelectronics)

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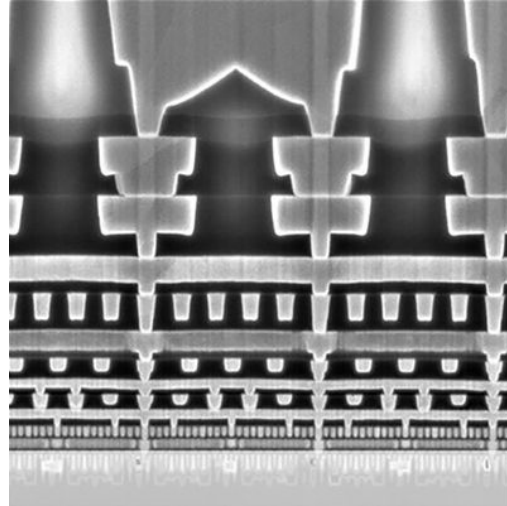
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16

Metal Stack in Modern Processes

• Metal stack

- Bottom layers have pitch that matches transistors
- Intermediate are 2-4x
- Top layers are wide and thick: Power distribution, clock



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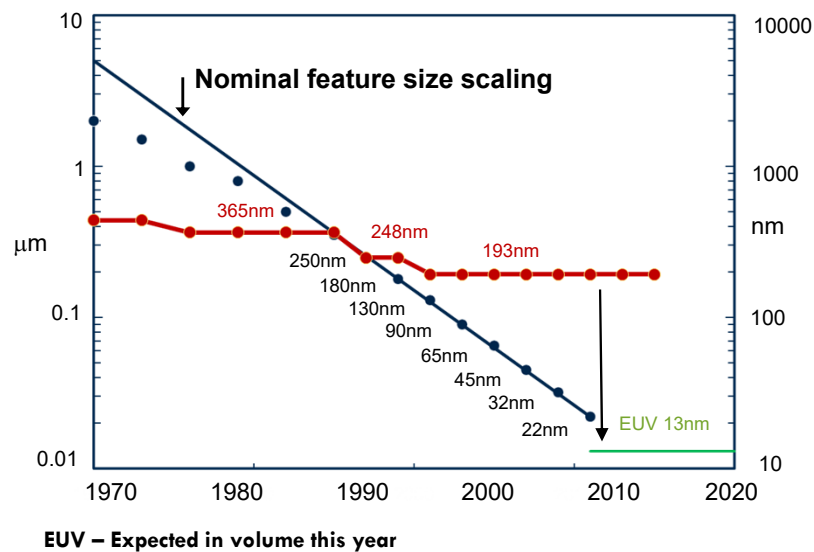
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Lithography Scaling



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Sub-Wavelength Lithography

- Light projected through a gap

193nm light

Mask

Light intensity

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Lithography Implications

- Forbidden directions

- Forbidden pitches

- Optical proximity correction (OPC)

?

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We Would Just Like a Square Contact...

- OPC vs. ILT

Optical Proximity Correction		Inverse Lithography Technology	
45 nm node	28 nm node	14 nm node	7 nm node
without OPC	normal OPC	normal ILT	ideal ILT
			

<https://semiengineering.com/what-happened-to-inverse-lithography/>

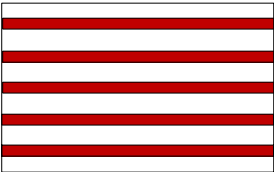
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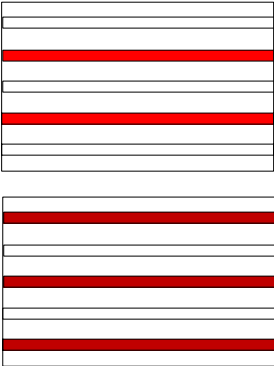
Multiple Patterning

- Double patterning (pitch-split double exposure)

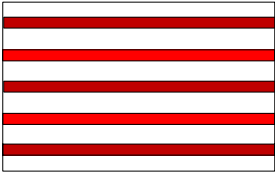
Starting layout



Split pattern





Overlay



With overlay misalignment

- “Layout coloring”
- 7nm process is quadruple patterned (w/o EUV)

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Lithography and Processing Takeaways

- 193nm lithography impacts many of the design rules in modern processes:
 - Preferred and forbidden directions
 - Forbidden pitches
 - Multiple patterning
- EUV relaxes many of the restrictions in sub 5nm processes

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Administrivia

- Semiconductor Workforce Fellowships in the area of SoC design
 - 8 undergraduate scholarships (4k each), applications due October 15
- Homework 4 is due today
 - No new homework this week
 - Homework 5 will be posted later this week, due next week
- No lab this week
 - Lab 6 (last) after the midterm
- Midterm 1 on October 7, 7-8:30pm
 - You will be assigned a classroom
 - One double-sided page of notes allowed
 - Material includes FPGAs

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MOS Transistors

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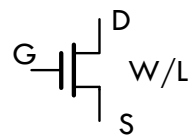


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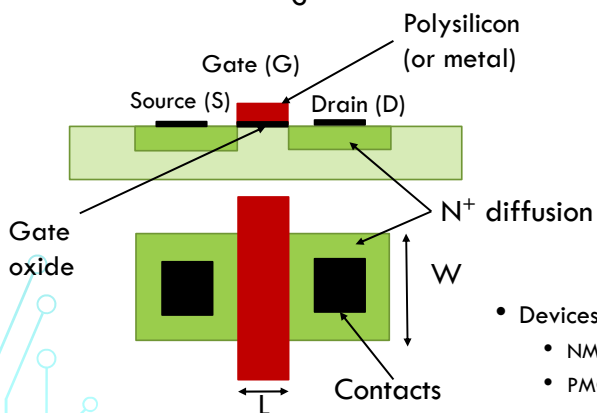
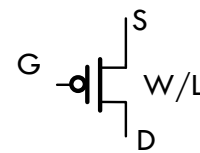
MOS Transistors

• Symbol

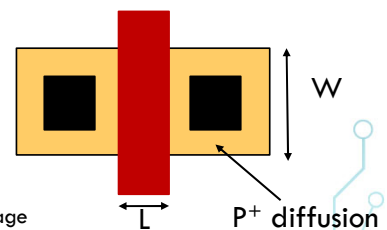
N-type
NMOS



P-type
PMOS



- Devices are symmetrical
 - NMOS: Drain is at higher voltage
 - PMOS: Source is at higher voltage



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Different Kinds of MOS Transistors

- Planar bulk CMOS
 - N-type NMOS
- FinFET

Intel 10nm IEDM 2017

W is discrete!

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Different Kinds of MOS Transistors

- Planar bulk CMOS
 - N-type NMOS
- Fully-depleted SOI

ST 28nm VLSI 2012

Buried oxide (or BOX)

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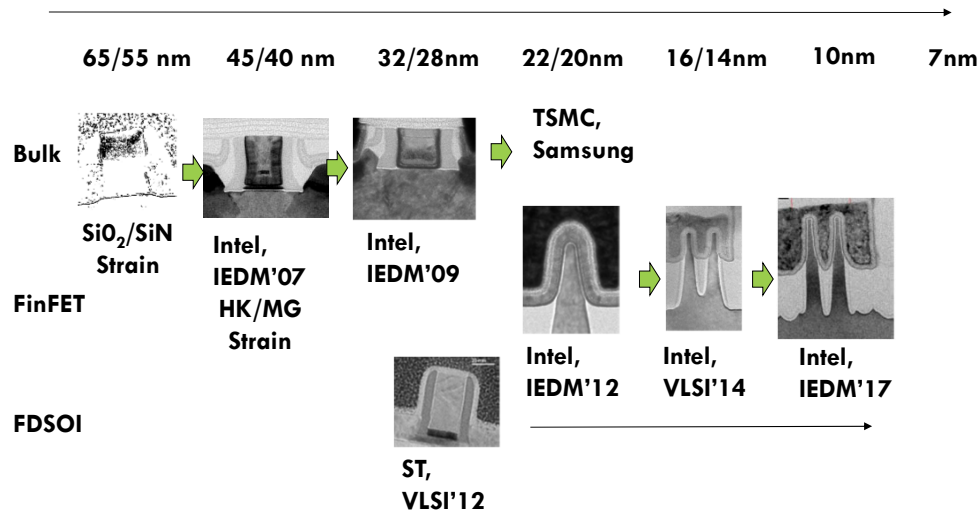
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Transistors are Changing

- From bulk to finFET and FDSOI



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Transistor Dimensions are Quantized

- FinFET widths are discrete ($W = kW_{\text{unit}}$)
 - k is an integer
- Lengths are quantized because of lithography
 - Also are quantized lower metal layers, contacts...

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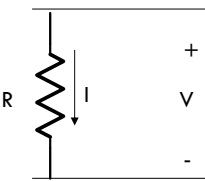
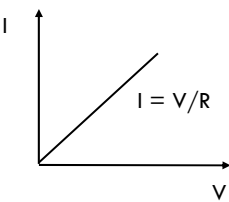

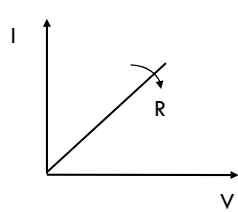
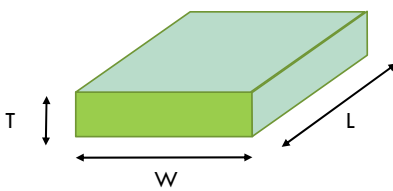
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Ohm's Law

- Resistors
 

- Variable resistors
 

- Physical resistors
 

$$R = \rho \frac{L}{TW}$$
 - In a planar process, designer controls W and L

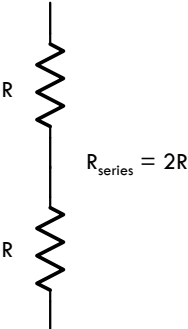
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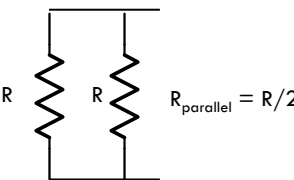
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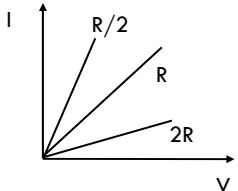
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Series and Parallel

- With two identical resistors, R
 

Equivalent to doubling length
- 

Equivalent to doubling width



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An n-Channel MOS Transistor

The diagram shows two cross-sectional views of an n-channel MOS transistor. The top view shows the transistor is off with $V_D = 0V$, $V_G = 0V$, and $V_S = 0V$. The current $I = 0$. The bottom view shows the transistor in a leakage state with $V_D > 0$, $V_G = 0V$, and $V_S = 0V$. The current $I > 0$. Both views show a p-type substrate with n+ source and drain regions, and a gate stack consisting of a polysilicon gate and a dielectric layer.

Polysilicon gate, dielectric, and substrate form a capacitor.

When $V_{GS} < V_{Th}$ transistor is off

$V_{DS} > 0$, transistor leaks
 $I_{DS} \sim nA$

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An n-Channel MOS Transistor

The diagram shows two cross-sectional views of an n-channel MOS transistor. The top view shows the transistor is off with $V_D = 0V$, $V_G = 0V$, and $V_S = 0V$. The current $I = 0$. The bottom view shows the transistor is on with $V_D > 0$, $V_G > V_{Th}$, and $V_S = 0V$. The current $I > 0$. Both views show a p-type substrate with n+ source and drain regions, and a gate stack consisting of a polysilicon gate and a dielectric layer. In the on-state, a small region near the surface is shown turning from p-type to n-type.

When $V_{GS} < V_{Th}$ transistor is off

$V_G > V_{Th}$, small region near the surface turns from p-type to n-type.

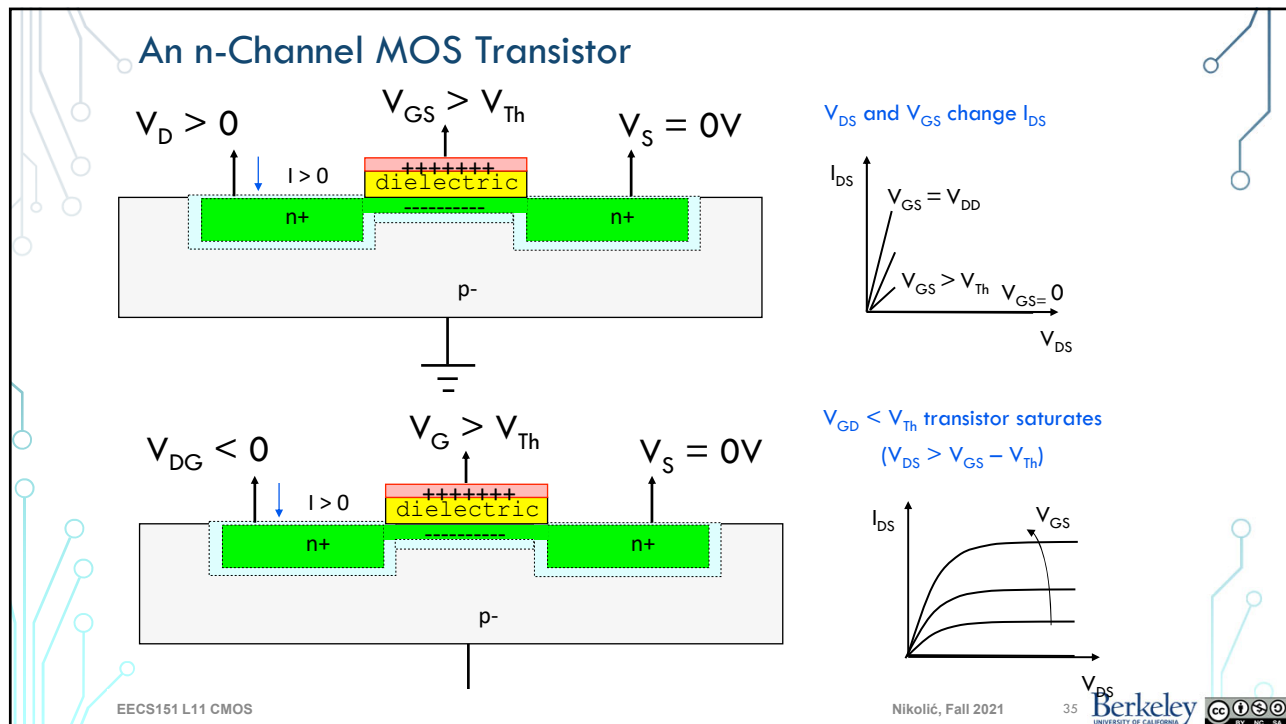
nFet is on.
Current is proportional to V_{DS}

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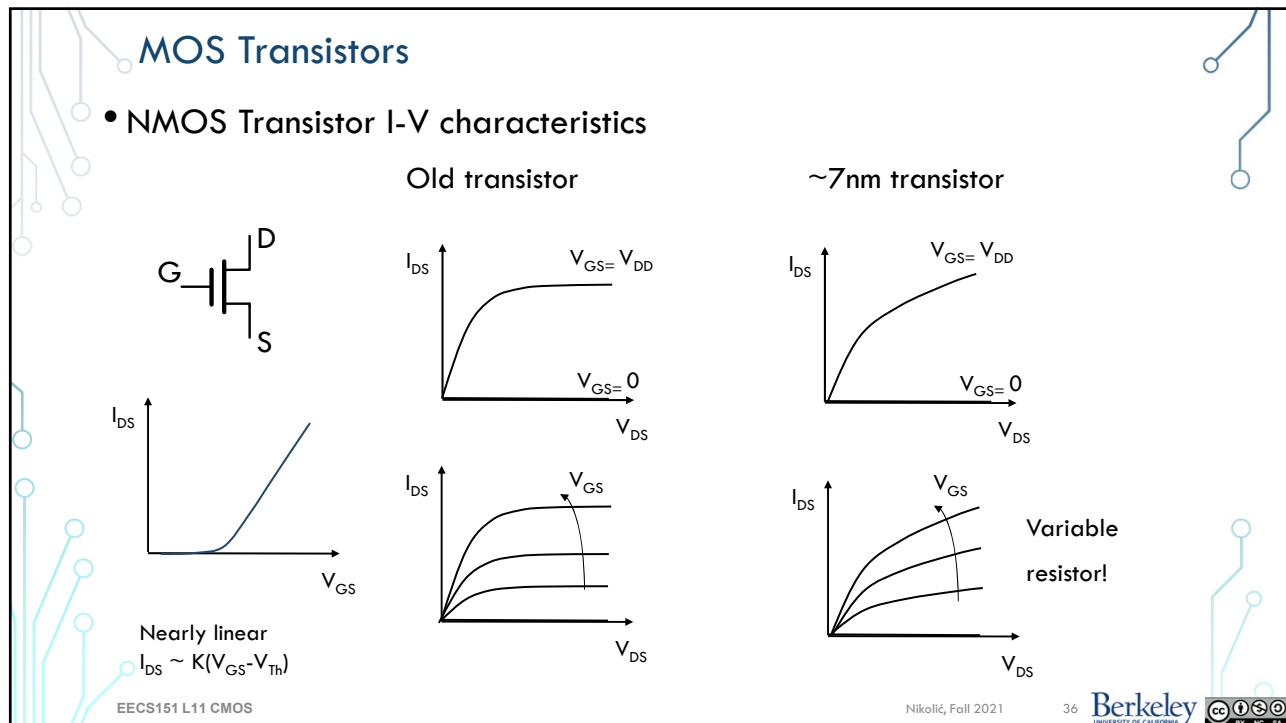
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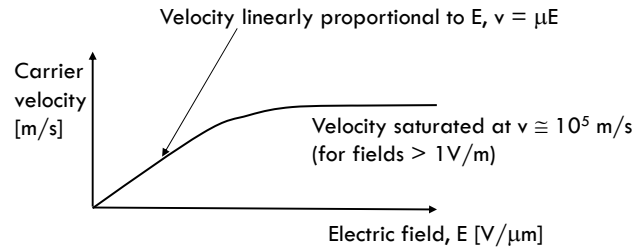
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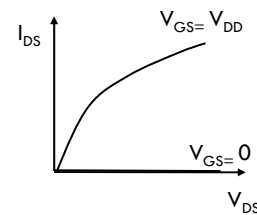
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Velocity Saturation

- Carrier velocity in the channel saturates



- All submicron transistors are velocity saturated
- Other effects (drain-induced barrier lowering) cause I_{DS} to increase in saturation



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Summary

- Core FPGA building blocks:
 - Configurable Logic Blocks (CLBs)
 - Configurable Interconnect
 - Switch boxes
- Modern FPGA Designs:
 - BRAMs, DSPs, and AI Engines
- CMOS process is used for producing chips
 - Planar bulk process used up to 28nm node
 - finFET used below the 22nm node
 - Also FDSOI, but we didn't talk about it

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